



Damage in Laser Materials: Proceedings of a Symposium Sponsored by the American Society for Testing and Materials and by the National Bureau of Standards, June 24-25, 1970, Nbs, Boulder, Colorado (Classic Reprint) (Paperback)

By Alexander J Glass

Forgotten Books, 2017. Paperback. Condition: New. Language: English . Brand New Book ***** Print on Demand *****. Excerpt from Damage in Laser Materials: Proceedings of a Symposium Sponsored by the American Society for Testing and Materials and by the National Bureau of Standards, June 24-25, 1970, Nbs, Boulder, Colorado Two speakers reported theoretical analyses of the stress induced in an otherwise homogeneous medium by the presence of an absorbing inclusion under intense illumination. Although there were points of disagreement between the two analyses, certain conclusions were obtained from both. The most damaging particles range in size from to cm, and it is precisely in this range that the non destructive detection of particulate inclusions is most difficult. Larger particles do not get heated to a temperature sufficiently high to cause damaging stress concentrations, while smaller particles do not intercept enough of the incident energy to cause damage. Increasing the thermal conductivity of the medium increases the damage threshold, as might be expected. It is significant that detailed modeling of this most fundamental damage process has only been carried out recently, although the role of particulate inclusions in the damage process has been known for many years. The models, though approximate,...



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